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Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields

### (standards.iteh.ai)

Elektromagnetische Verträglichkeit (EMV) - Teil 4-6: Prüf- und Messverfahren - Störfestigkeit gegen leitungsgeführte Störgrößen, induziert durch hochfrequente Felder https://standards.iteh.ai/catalog/standards/sist/e90e14b9-ebd4-49a5-9d75-af080b4c81eb/sist-en-61000-4-6-2008

Compatibilité électromagnétique (CEM) - Partie 4-6: Techniques d'essai et de mesure - Immunité aux perturbations conduites, induites par les champs radioélectriques

Ta slovenski standard je istoveten z: EN 61000-4-6:2007

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### EUROPEAN STANDARD

### EN 61000-4-6

## NORME EUROPÉENNE **EUROPÄISCHE NORM**

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ICS 33.100.20

Supersedes EN 61000-4-6:1996 + A1:2001 and EN 61000-4-6:1996/IS1:2004

**English version** 

Electromagnetic compatibility (EMC) -Part 4-6: Testing and measurement techniques -Immunity to conducted disturbances, induced by radio-frequency fields

(IEC 61000-4-6:2003 + A1:2004 + A2:2006)

Compatibilité électromagnétique (CEM) -Partie 4-6: Techniques d'essai et de mesure -Immunité aux perturbations conduites, induites par les champs radioélectriques

(CEI 61000-4-6:2003 + A1:2004 AND ARD

A2:2006)

Elektromagnetische Verträglichkeit (EMV) -Teil 4-6: Prüf- und Messverfahren -Störfestigkeit gegen leitungsgeführte Störgrößen, induziert durch phochfrequente Felder

(IEC 61000-4-6:2003 + A1:2004 +

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#### SIST EN 61000-4-6:2008

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This European Standard was approved by CENELEC on 2007-06-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

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## **CENELEC**

European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

#### **Foreword**

The text of the International Standard IEC 61000-4-6:2006 and its amendments 1:2004 and 2:2006, prepared by SC 77B, High frequency phenomena, of IEC TC 77, Electromagnetic compatibility, was submitted to the formal vote and was approved by CENELEC as EN 61000-4-6 on 2007-06-01 without any modification.

This European Standard supersedes EN 61000-4-6:1996 + A1:2001 and EN 61000-4-6:1996/IS1:2004.

The following dates were fixed:

 latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement

(dop) 2008-06-01

latest date by which the national standards conflicting with the EN have to be withdrawn

(dow) 2010-06-01

Annex ZA has been added by CENELEC.

## **Endorsement notice**

The text of the International Standard IEC 61000-4-6:2006 + A1:2004 + A2:2006 was approved by CENELEC as a European Standard without any modification. R. F. V. F. W.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 61000-4-3 NOTE Harmonized as EN 61000-4-3:2002 (not modified).

standards, iteh ai/catalog/standards/sist/e90e14b9-ebd4-49a5-9d75-NOTE Harmonized as EN 55020:2002 (not modified).

CISPR 20

# Annex ZA (normative)

# Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	EN/HD	<u>Year</u>
IEC 60050-161	_1)	International Electrotechnical Vocabulary (IEV) - Chapter 161: Electromagnetic compatibility	-	-

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<sup>1)</sup> Undated reference.



#### Corrigendum to EN 61000-4-6:2007

English version

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#### **Foreword**

In the first paragraph, replace "IEC 61000-4-6:2006" by "IEC 61000-4-6:2003".

#### **Endorsement notice**

Replace "IEC 61000-4-6:2006" by "IEC 61000-4-6:2003".

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# NORME INTERNATIONALE

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Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields

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### **CONTENTS**

FOF	REWC	PRD	4		
INT	RODU	JCTION	6		
1		e and object			
2	Norm	ative references	7		
3	Definitions				
4	Gene	ral	9		
5	Test	levels	10		
6	Test	equipment	10		
	6.1	Test generator	10		
	6.2	Coupling and decoupling devices	11		
	6.3	Verification of the common mode impedance at the EUT port of coupling and decoupling devices	14		
	6.4	Setting of the test generator			
7	Test	set-up for table-top and floor-standing equipment	16		
	7.1	Rules for selecting injection methods and test points	16		
	7.2	Procedure for CDN injection application	18		
	7.3	Procedure for clamp injection when the common-mode impedance requirements can be met	18		
	7.4	Procedure for clamp injection when the common-mode impedance			
	7.5	Procedure for direct injection of the state			
	7.6	EUT comprisingrassingle unitalog/standards/sist/e90e14b9-ebd4-49a5-9d75-			
	7.7	EUT comprising several Whits 81eb/sist-en-61000-4-6-2008			
8	Test	procedure			
9	Evalu	ration of the test results	21		
10	Test	report	22		
Δnn	εν Δ	(normative) Additional information regarding clamp injection	34		
		(informative) Selection criteria for the frequency range of application			
		(informative) Guide for selecting test levels			
		(informative) Information on coupling and decoupling networks			
		· · · · · · · · · · · · · · · · · · ·			
		(informative) Information for the test generator specification(informative) Test set-up for large EUTs			
AIII	ex r (	(informative) Test set-up for large EUTs	47		
Bibl	iograp	phy	50		
Figu	Figure 1 – Rules for selecting the injection method				
Figu	Figure 2 – Immunity test to RF conducted disturbances2				
Figu	Figure 3 – Test generator set-up25				
		- Definition of the wave shapes occurring at the output of the EUT	0.5		
•	port of a coupling device (e.m.f. of test level 1)				
Figu	ıre 5 -	- Principle of coupling and decoupling	28		

Figure 6 – Principle of coupling and decoupling according to the clamp injection method .	28
Figure 7 – Details of set-ups and components to verify the essential characteristics of coupling and decoupling devices and the 150 $\Omega$ to 50 $\Omega$ adapters	30
Figure 8 – Set-up for level setting (see 6.4.1)	
Figure 9 – Example of test set-up with a single unit system	32
Figure 10 – Example of a test set-up with a multi-unit system	33
Figure A.1 – Circuit for level setting set-up in a 50 $\Omega$ test Jig	35
Figure A.2 – The 50 Ω test jig construction	
Figure A.3 – Construction details of the EM clamp	
Figure A.4 – Concept of the EM clamp (electromagnetic clamp)	37
Figure A.5 – Coupling factor of the EM clamp	37
Figure A.6 – General principle of a test set-up using Injection clamps	38
Figure A.7 – Example of the test unit locations on the ground plane when using injection clamps (top view)	38
Figure B.1 – Start frequency as function of cable length and equipment size	40
Figure D.1 – Example of a simplified diagram for the circuit of CDN-S1 used with screened cables (see 6.2.1)	43
Figure D.2 – Example of simplified diagram for the circuit of CDN-M1/-M2/-M3 used with unscreened supply (mains) lines (see 6.2.2.1)	43
used with unscreened supply (mains) lines (see 6.2.2.1)	44
Figure D.4 – Example of a simplified diagram for the circuit of a CDN-T2, used with an unscreened balanced pair (see 6.2.2.2)	
Figure D.5 – Example of a simplified diagram of the circuit of a CDN-T49d75- used with unscreened balanced pairs (see 6.2.2.2) 1000-4-6-2008	
Figure D.6 – Example of a simplified diagram of the circuit of a CDN-T8 used with unscreened balanced pairs (see 6.2.2.2)	45
Figure F.1 – Example of large EUT test set-up with elevated horizontal ground reference plane	48
Figure F.2 – Example of large EUT test set-up with vertical ground reference plane	49
Table 1 – Test levels	10
Table 2 – Characteristics of the test generator	11
Table 3 – Main parameter of the combination of the coupling and decoupling device	11
Table B.1 – Main parameter of the combination of the coupling and decoupling device when the frequency range of test is extended above 80 MHz	39
Table E.1 – Required power amplifier output power to obtain a test level of 10 V	46

#### INTERNATIONAL ELECTROTECHNICAL COMMISSION

#### **ELECTROMAGNETIC COMPATIBILITY (EMC) –**

#### Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields

#### **FOREWORD**

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 61000-4-6 has been prepared by subcommittee 77B: High-frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

This standard forms part 4-6 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107, *Electromagnetic compatibility – Guide to the drafting of electromagnetic compatibility publications*.

This consolidated version of IEC 61000-4-6 consists of the second edition (2003) [documents 77B/377/FDIS and 77B/384/RVD], its amendment 1 (2004) [documents 77B/426/FDIS and 77B/431/RVD] and its amendment 2 (2006) [documents 77B/492/FDIS and 77B/502/RVD].

The technical content is therefore identical to the base edition and its amendments and has been prepared for user convenience.

It bears the edition number 2.2.

A vertical line in the margin shows where the base publication has been modified by amendments 1 and 2.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of the base publication and its amendments will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed.
- withdrawn,
- · replaced by a revised edition, or
- · amended.

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#### INTRODUCTION

**-6-**

IEC 61000 is published in separate parts according to the following structure:

#### Part 1: General

General considerations (introduction, fundamental principles)
Definitions, terminology

#### Part 2: Environment

Description of the environment Classification of the environment Compatibility levels

#### Part 3: Limits

**Emission limits** 

Immunity limits (in so far as they do not fall under the responsibility of the product committees)

#### Part 4: Testing and measurement techniques

Measurement techniques STANDARD PREVIEW
Testing techniques (standards.iteh.ai)

#### Part 5: Installation and mitigation guidelines

Installation guidelines SIST EN 61000-4-6:2008 https://standards.iteh.ai/catalog/standards/sist/e90e14b9-ebd4-49a5-9d75-Mitigation methods and devices at 80b4c81eb/sist-en-61000-4-6-2008

#### Part 6: Generic standards

#### Part 9: Miscellaneous

Each part is further subdivided into several parts, published either as international standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example: 61000-6-1).

This part is an international standard which gives immunity requirements and test procedure related to conducted disturbances induced by radio-frequency fields.

#### **ELECTROMAGNETIC COMPATIBILITY (EMC) -**

#### Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields

#### 1 Scope and object

This part of IEC 61000-4 relates to the conducted immunity requirements of electrical and electronic equipment to electromagnetic disturbances coming from intended radio-frequency (RF) transmitters in the frequency range 9 kHz up to 80 MHz. Equipment not having at least one conducting cable (such as mains supply, signal line or earth connection) which can couple the equipment to the disturbing RF fields is excluded.

NOTE 1 Test methods are defined in this part for measuring the effect that conducted disturbing signals, induced by electromagnetic radiation, have on the equipment concerned. The simulation and measurement of these conducted disturbances are not adequately exact for the quantitative determination of effects. The test methods defined are structured for the primary objective of establishing adequate repeatability of results at various facilities for quantitative analysis of effects.

The object of this standard is to establish a common reference for evaluating the functional immunity of electrical and electronic equipment when subjected to conducted disturbances induced by radio-frequency fields. The test method documented in this part of IEC 61000 describes a consistent method to assess the immunity of an equipment or system against a defined phenomenon.

NOTE 2 As described in IEC Guide 107, this is a basic EMC publication for use by product committees of the IEC. As also stated in Guide 107, the IEC product committees are responsible for determining whether this immunity test standard should be applied or not, and if applied, they are responsible for determining the appropriate test levels and performance criteria. TC 77 and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular immunity tests for their products.

#### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050(161), International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic compatibility

#### 3 Definitions

For the purpose of this part of IEC 61000, the definitions given in IEC 60050(161) as well as the following definitions apply.

#### 3.1

#### artificial hand

electrical network simulating the impedance of the human body under average operational conditions between a hand-held electrical appliance and earth

[IEV 161-04-27]

NOTE The construction should be in accordance with CISPR 16-1.

#### 3.2

#### auxiliary equipment

#### ΔF

equipment necessary to provide the equipment under test (EUT) with the signals required for normal operation and equipment to verify the performance of the EUT

-8-

#### 3.3

#### clamp injection

clamp injection is obtained by means of a clamp-on "current" injecting device on the cable:

- current clamp: a transformer, the secondary winding of which consists of the cable into which the injection is made;
- electromagnetic clamp (EM clamp): injection device with combined capacitive and inductive coupling

#### 3.4

#### common-mode impedance

ratio of the common mode voltage and the common-mode current at a certain port

NOTE This common mode impedance can be determined by applying a unity common mode voltage between the terminal(s) or screen of that port and a reference plane (point). The resulting common mode current is then measured as the vectorial sum of all currents flowing through these terminal(s) or screen (see also Figures 8a and 8b).

# 3.5 coupling factor iTeh STANDARD PREVIEW

ratio given by the open-circuit voltage (e.m.f.) obtained at the EUT port of the coupling (and decoupling) device divided by the open-circuit voltage obtained at the output of the test generator

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3.6 https://standards.iteh.ai/catalog/standards/sist/e90e14b9-ebd4-49a5-9d75-

#### coupling network

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electrical circuit for transferring energy from one circuit to another with a defined impedance

NOTE Coupling and decoupling devices can be integrated into one box (coupling and decoupling network (CDN)) or they can be in separate networks.

#### 3.7

#### coupling/decoupling network

#### CDN

electrical circuit incorporating the functions of both the coupling and decoupling networks

#### 3.8

#### decoupling network

electrical circuit for preventing test signals applied to the EUT from affecting other devices, equipment or systems that are not under test

#### 3.9

#### test generator

generator (RF generator, modulation source, attenuators, broadband power amplifier and filters) capable of generating the required test signal (see Figure 3)

#### 3.10

#### electromotive force

#### e.m.f.

voltage at the terminals of the ideal voltage source in the representation of an active element [IEV 131-01-38:1978]

#### 3.11

#### measurement result

 $U_{\rm mr}$ 

voltage reading of the measurement equipment

#### voltage standing wave ratio

ratio of a maximum to an adjacent minimum voltage magnitude along the line

#### General

The source of disturbance covered by this part of IEC 61000 is basically an electromagnetic field, coming from intended RF transmitters, that may act on the whole length of cables connected to installed equipment. The dimensions of the disturbed equipment, mostly a subpart of a larger system, are assumed to be small compared with the wavelengths involved. The in-going and outgoing leads (e.g. mains, communication lines, interface cables) behave as passive receiving antenna networks because of their length, which can be several wavelengths.

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Between those cable networks, the susceptible equipment is exposed to currents flowing "through" the equipment. Cable systems connected to an equipment are assumed to be in resonant mode ( $\lambda/4$ ,  $\lambda/2$  open or folded dipoles) and as such are represented by coupling and decoupling devices having a common-mode impedance of 150  $\Omega$  with respect to a ground reference plane. Where possible the EUT is tested by connecting it between two 150  $\Omega$ common-mode impedance connections: one providing an RF source and the other providing a return path for the current.

This test method subjects the EUT to a source of disturbance comprising electric and magnetic fields, simulating those coming from intentional RF transmitters. These disturbing fields (E and H) are approximated by the electric and magnetic near-fields resulting from the voltages and currents caused by the test set-up as shown in Figure 2a.

The use of coupling and decoupling devices to apply the disturbing signal to one cable at the time, while keeping all other cables non-excited, see Figure 2b, can only approximate the real situation where disturbing sources act on all cables simultaneously, with a range of different amplitudes and phases.

Coupling and decoupling devices are defined by their characteristics given in 6.2. Any coupling and decoupling device fulfilling these characteristics can be used. The coupling and decoupling networks in Annex D are only examples of commercially available networks.